



FOR IMMEDIATE RELEASE

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**Aehr Test Systems to Announce Fourth Quarter Fiscal 2016 Financial Results  
on July 26, 2016**

**Fremont, CA (July 14, 2016)** – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it will report financial results for its fiscal 2016 fourth quarter and full year ended May 31, 2016 on Tuesday, July 26, 2016 following the close of the market. The Company will host a conference call and webcast at 5:00 p.m. Eastern time to discuss the results.

**What:** Aehr Test Systems fourth quarter fiscal 2016 financial results conference call

**When:** Tuesday, July 26<sup>th</sup> at 5:00 p.m. Eastern Time (2:00 p.m. PT)

**Dial in Number:** To access the live call, dial **888-510-1785** (US and Canada) or **719-457-2661** (International) and give the participant passcode **4651520**.

**Webcast:** To access the live webcast, please visit the investor relations section at [www.aehr.com](http://www.aehr.com).

**Call Replay:** A phone replay of the call will be available approximately two hours following the end of the call through 8:00 p.m. ET on Tuesday, August 2, 2016. To access the replay dial-in information, please click [here](#).

**About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and WaferPak contactors. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. For more information, please visit Aehr Test's website at [www.aehr.com](http://www.aehr.com).

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